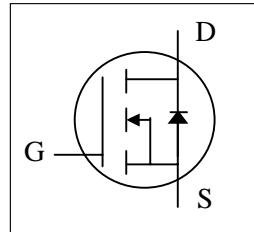
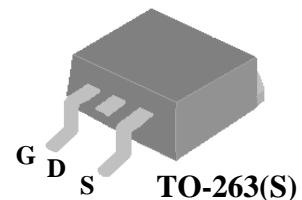




- ▼ Simple Drive Requirement
- ▼ Ultra-low On-resistance
- ▼ Fast Switching Characteristic
- ▼ RoHS Compliant & Halogen-Free



$BV_{DSS}$	40V
$R_{DS(ON)}$	2.6mΩ



## Description

AP4N2R6 series are from Advanced Power innovative design and silicon process technology to achieve the lowest possible on-resistance and fast switching performance. It provides the designer with an extreme efficient device for use in a wide range of power applications.

The TO-263 package is widely preferred for all commercial-industrial surface mount applications using infrared reflow technique and suited for high current application due to the low connection resistance.

## Absolute Maximum Ratings@ $T_j=25^\circ\text{C}$ (unless otherwise specified)

Symbol	Parameter	Rating	Units
$V_{DS}$	Drain-Source Voltage	40	V
$V_{GS}$	Gate-Source Voltage	<u>+20</u>	V
$I_D @ T_C = 25^\circ\text{C}$	Drain Current, $V_{GS} @ 10\text{V}^4$ (Silicon Limited)	150	A
$I_D @ T_C = 25^\circ\text{C}$	Drain Current, $V_{GS} @ 10\text{V}^4$	130	A
$I_D @ T_C = 100^\circ\text{C}$	Drain Current, $V_{GS} @ 10\text{V}$	95	A
$I_{DM}$	Pulsed Drain Current <sup>1</sup>	400	A
$P_D @ T_C = 25^\circ\text{C}$	Total Power Dissipation	104	W
$P_D @ T_A = 25^\circ\text{C}$	Total Power Dissipation	3.12	W
$E_{AS}$	Single Pulse Avalanche Energy <sup>3</sup>	45	mJ
$T_{STG}$	Storage Temperature Range	-55 to 150	°C
$T_J$	Operating Junction Temperature Range	-55 to 150	°C

## Thermal Data

Symbol	Parameter	Value	Units
$R_{thj-c}$	Maximum Thermal Resistance, Junction-case	1.2	°C/W
$R_{thj-a}$	Maximum Thermal Resistance, Junction-ambient (PCB mount) <sup>5</sup>	40	°C/W



# AP4N2R6S

## Electrical Characteristics@ $T_j=25^\circ C$ (unless otherwise specified)

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Units
$BV_{DSS}$	Drain-Source Breakdown Voltage	$V_{GS}=0V, I_D=250\mu A$	40	-	-	V
$R_{DS(ON)}$	Static Drain-Source On-Resistance <sup>2</sup>	$V_{GS}=10V, I_D=40A$	-	-	2.6	$m\Omega$
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=250\mu A$	2	-	5	V
$g_{fs}$	Forward Transconductance	$V_{DS}=5V, I_D=40A$	-	140	-	S
$I_{DSS}$	Drain-Source Leakage Current	$V_{DS}=32V, V_{GS}=0V$	-	-	10	$\mu A$
$I_{GSS}$	Gate-Source Leakage	$V_{GS}= \pm 20V, V_{DS}=0V$	-	-	$\pm 100$	nA
$Q_g$	Total Gate Charge	$I_D=40A$	-	87	139	nC
$Q_{gs}$	Gate-Source Charge	$V_{DS}=32V$	-	20	-	nC
$Q_{gd}$	Gate-Drain ("Miller") Charge	$V_{GS}=10V$	-	23	-	nC
$t_{d(on)}$	Turn-on Delay Time	$V_{DS}=20V$	-	15	-	ns
$t_r$	Rise Time	$I_D=40A$	-	63	-	ns
$t_{d(off)}$	Turn-off Delay Time	$R_G=1.6\Omega$	-	36	-	ns
$t_f$	Fall Time	$V_{GS}=10V$	-	12	-	ns
$C_{iss}$	Input Capacitance	$V_{GS}=0V$	-	5100	8160	pF
$C_{oss}$	Output Capacitance	$V_{DS}=20V$	-	720	-	pF
$C_{rss}$	Reverse Transfer Capacitance	f=1.0MHz	-	360	-	pF
$R_g$	Gate Resistance	f=1.0MHz	-	1.2	2.4	$\Omega$

## Source-Drain Diode

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Units
$V_{SD}$	Forward On Voltage <sup>2</sup>	$I_S=40A, V_{GS}=0V$	-	-	1.2	V
$t_{rr}$	Reverse Recovery Time	$I_S=40A, V_{GS}=0V$	-	16	-	ns
$Q_{rr}$	Reverse Recovery Charge	dl/dt=100A/ $\mu s$	-	5.4	-	nC

## Notes:

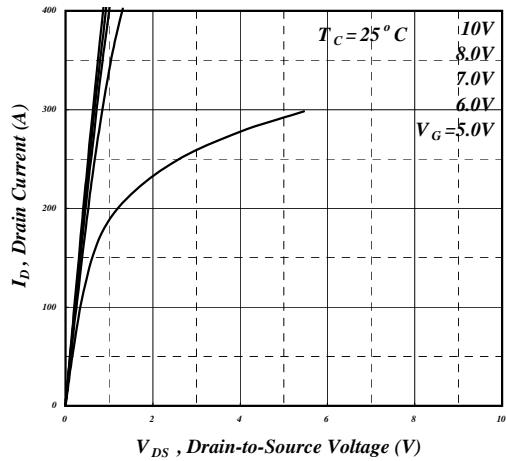
- 1.Pulse width limited by Max. junction temperature.
- 2.Pulse test
- 3.Starting  $T_j=25^\circ C$  ,  $V_{DD}=25V$  ,  $L=0.1mH$  ,  $R_G=25\Omega$  ,  $V_{GS}=10V$
- 4.Package limitation current is 130A .
- 5.Surface mounted on 1 in<sup>2</sup> copper pad of FR4 board

THIS PRODUCT IS SENSITIVE TO ELECTROSTATIC DISCHARGE, PLEASE HANDLE WITH CAUTION.

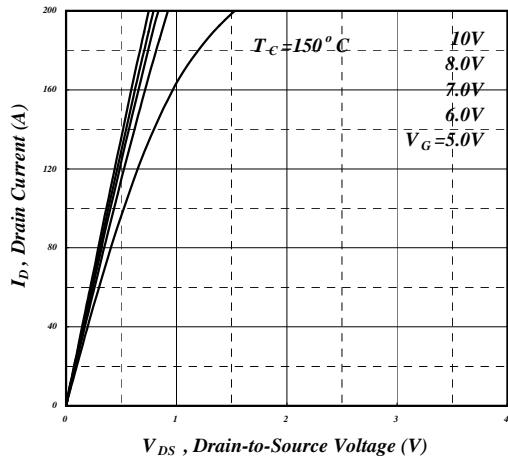
USE OF THIS PRODUCT AS A CRITICAL COMPONENT IN LIFE SUPPORT OR OTHER SIMILAR SYSTEMS IS NOT AUTHORIZED.

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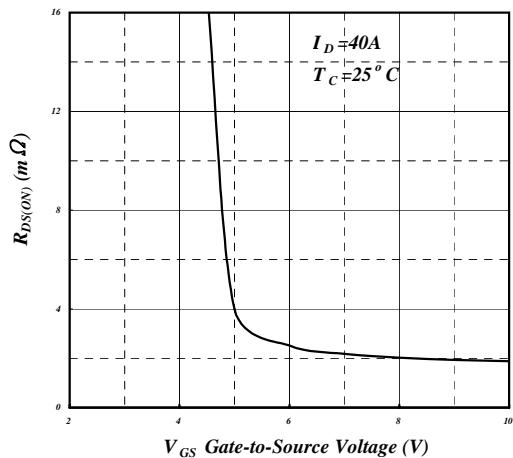
APEC RESERVES THE RIGHT TO MAKE CHANGES WITHOUT FURTHER NOTICE TO ANY PRODUCTS HEREIN TO IMPROVE RELIABILITY, FUNCTION OR DESIGN.



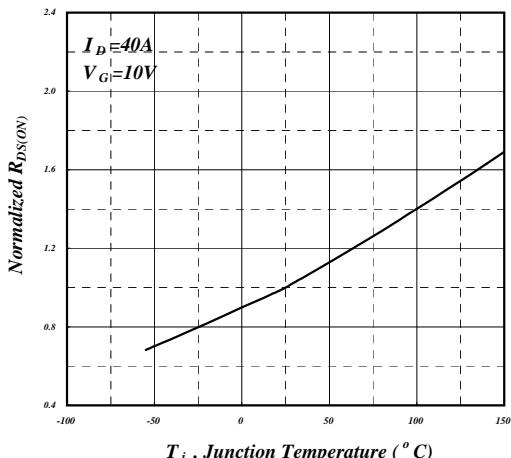
**Fig 1. Typical Output Characteristics**



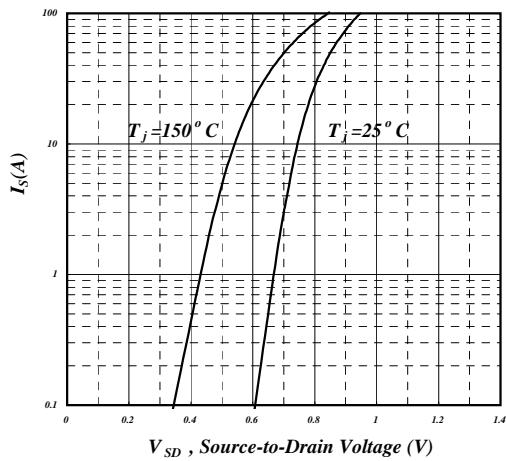
**Fig 2. Typical Output Characteristics**



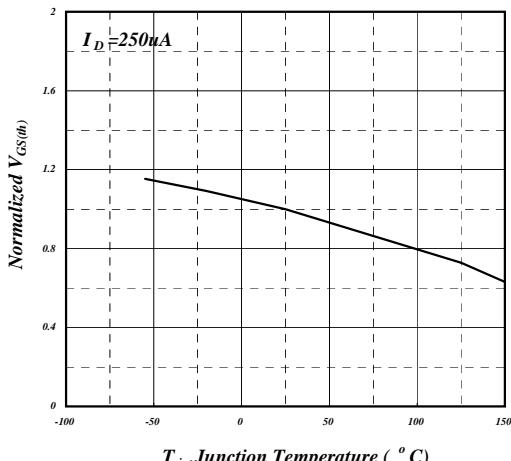
**Fig 3. On-Resistance v.s. Gate Voltage**



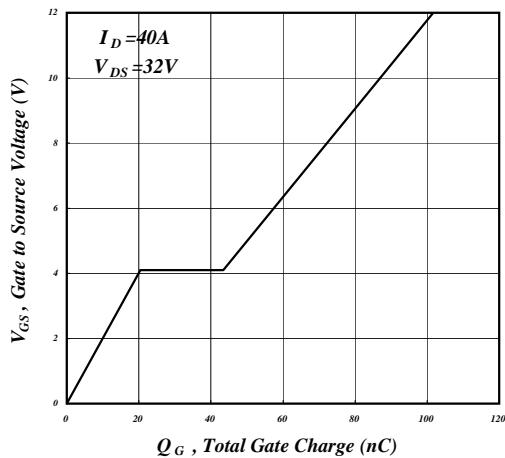
**Fig 4. Normalized On-Resistance v.s. Junction Temperature**



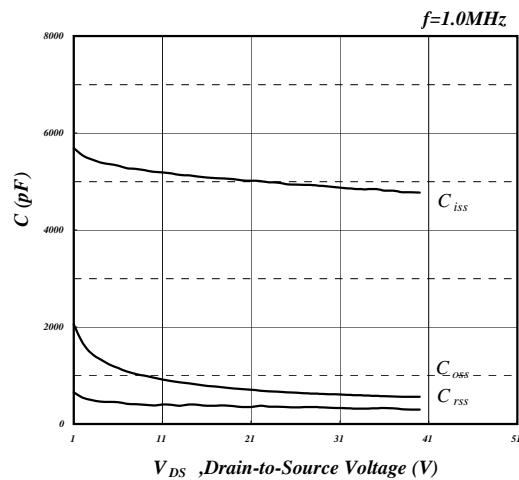
**Fig 5. Forward Characteristic of Reverse Diode**



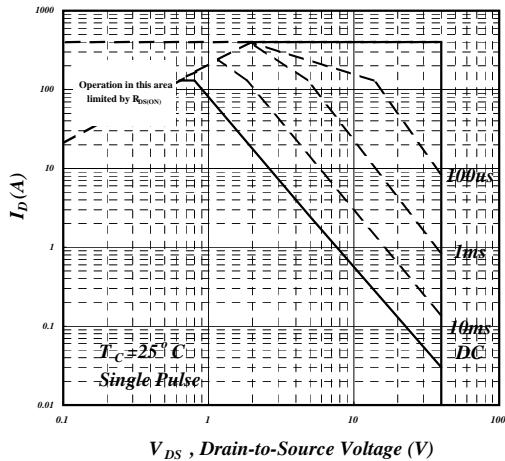
**Fig 6. Gate Threshold Voltage v.s. Junction Temperature**



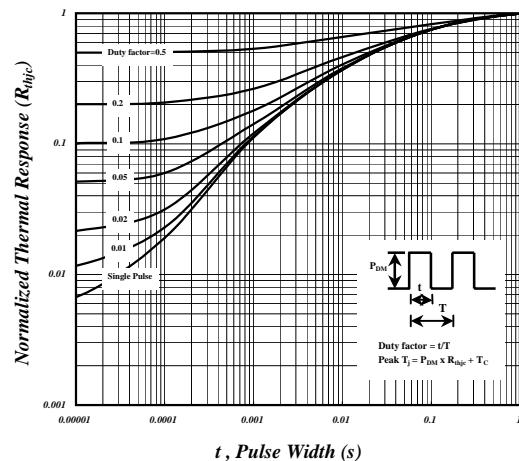
**Fig 7. Gate Charge Characteristics**



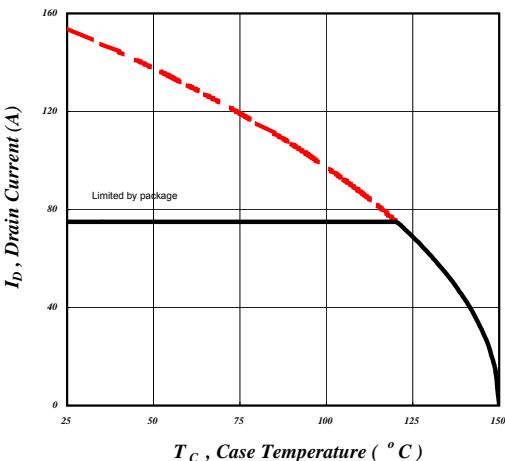
**Fig 8. Typical Capacitance Characteristics**



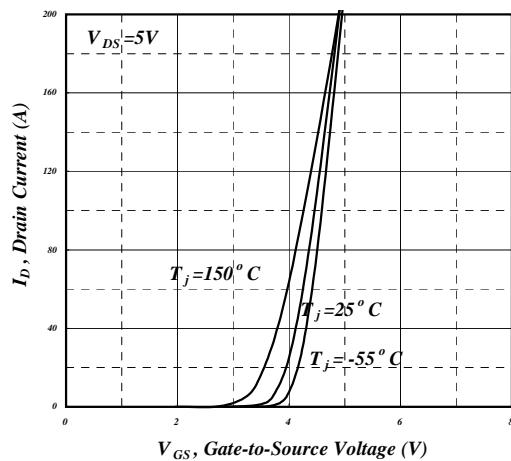
**Fig 9. Maximum Safe Operating Area**



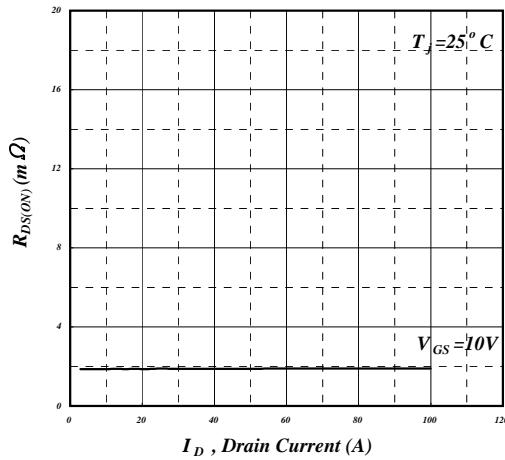
**Fig 10. Effective Transient Thermal Impedance**



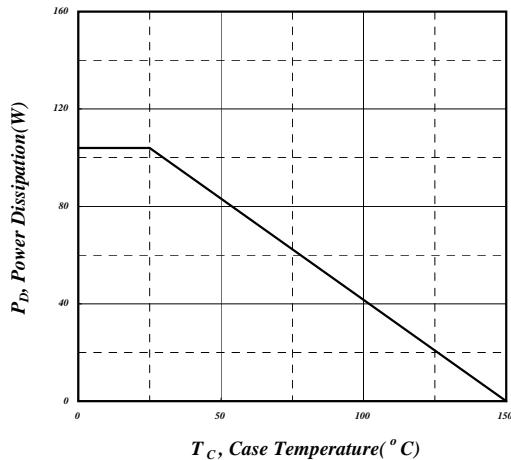
**Fig 11. Drain Current v.s. Case Temperature**



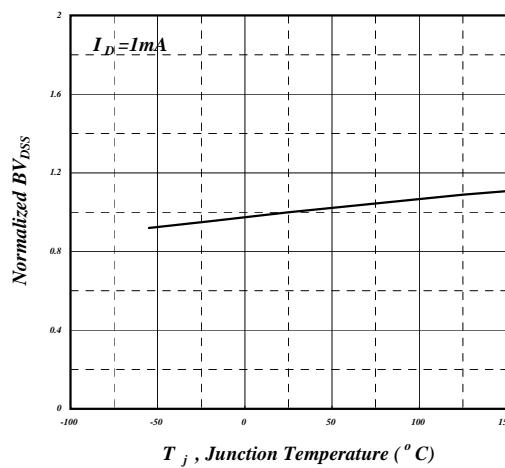
**Fig 12. Transfer Characteristics**



**Fig 13. Typ. Drain-Source on State Resistance**



**Fig 14. Total Power Dissipation**



**Fig 15. Normalized  $BV_{DSS}$  v.s. Junction**



**AP4N2R6S**

## **MARKING INFORMATION**

